

## **Quarterly Reliability Monitoring Results**

## Quarters: Q1/2022 to Q4/2023

Based on structural similarity

| Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test |                             | User Part Number  |              |           |            |           |  |
|--|-----------------------------|---|--------------|-----------|------------|-----------|--|
|  |                             | BAS21AW-Q   |              |           |            |           |  |
|  |                             | Part Description  |              |           |            |           |  |
|  |                             | Nexperia DHAM Small Signal Bipolar Diode                    |              |           |            |           |  |
|  |                             | SMD package   |              |           |            |           |  |
|  |                             | Test Conditions   | Duration     | # Lots    | # Quantity | # Rejects |  |
|  | TEST                        |   |              |           |            |           |  |
|  | Pre- and Post-Stress        |   |              |           |            |           |  |
| # E1   | Electrical Test             | Tamb = 25 °C  | N/A          | see below | all parts  | see below |  |
|  |                             | JESD22-A113   |              |           |            |           |  |
|  |                             | Bake Tamb = 125 °C  | 24 hours     |           |            |           |  |
|  | PC                          | Soak Tamb = 85 °C, RH = 85%                                 | 168 hours    |           |            |           |  |
| # A1   | Preconditioning             | Reflow soldering  | 3 cycles     | 1514      | 64430      | 0         |  |
|  |                             | MIL-STD-750-1   |              |           |            |           |  |
|  | HTRB                        | M1038 Method A  |              |           |            |           |  |
|  | High Temperature Reverse    | Tj = Tjmax, Vr = 100% of max. datasheet                     |              |           |            |           |  |
| # B1   | Bias                        | reverse voltage   | 1000 hours   | 110       | 4920       | 0         |  |
|  |                             |   |              |           |            |           |  |
|  | TC                          | JESD22-A104   |              |           |            |           |  |
| # A4   | Temperature Cycling         | -65 °C to Tjmax, not to exceed 150°C                        | 1000 cycles  | 311       | 14080      | 0         |  |
|  | UHAST                       | JESD22-A118   |              |           |            |           |  |
| # A3 <b>or</b>   | Unbiased HAST               | Tamb = 130 °C, RH = 85 %                                    |              |           |            |           |  |
| F AS UI  | Olibiased HAST              | · · · · · · · · · · · · · · · · · · ·                       | - 96 hours   | 311       | 14080      | 0         |  |
| # A3 alt   | AC                          | JESD22-A102   |              |           |            |           |  |
|  | Autoclave                   | Tamb = 121 °C, RH = 100 %<br>Pressure = 205 kPa (29.7 psia) |              |           |            |           |  |
| F A3 alt   | Autociave                   | riessule = 203 kra (29.7 psia)                              |              |           |            |           |  |
|  | H3TRB                       | JESD22-A101   |              |           |            |           |  |
|  | High Humidity High          | Tamb = 85 °C, RH = 85%, VR = 80 % of                        |              |           |            |           |  |
| # A2 alt   |                             | rated reverse voltage <sup>[1]</sup>                        | 1000 hours   | 311       | 14080      | 0         |  |
| # MZ dil   | peratare recreive blus      | MIL-STD-750 Method 1037                                     | 1000 1100/15 | J11       | 1 1000     |           |  |
|  | IOL                         | ton = toff, devices powered to insure $\Delta T_i$ =        |              |           |            |           |  |
| # A5   | Intermittent Operating Life |   | 1000 hours   | 312       | 14120      | 0         |  |
|  | End operating Line          |   | 2000 1100/3  | J12       | - 1120     |           |  |
|  | RSH                         | JESD22-A111   |              |           |            |           |  |
| # C8   | Resistance to Solder Heat   |   | 10 s         | 269       | 8070       | 0         |  |
|  | SD                          |   |              |           |            | -         |  |
|  |                             |   |              |           |            |           |  |

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1)
Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

| Wafer Fab | Technology                 | Quantity | Rejects | Failure Rate (FIT) | MTTF (hrs) |
|-----------|----------------------------|----------|---------|--------------------|------------|
| Nexperia  |                            |          |         |                    |            |
| DHAM      | Small Signal Bipolar Diode | 4920     | 0       | 0,86               | 1,16E+09   |

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